

# Fast switching diode chip in Emitter Controlled Technology

### Features:

- 1200V technology 120 μm chip
- · soft, fast switching
- low reverse recovery charge
- small temperature coefficient
- qualified according to JEDEC for target applications

#### Recommended for:

 power modules and discrete devices



## **Applications:**

SMPS, resonant applications, drives

| Chip Type    | $V_{R}$ | <i>I</i> <sub>Fn</sub> | Die Size                  | Package      |
|--------------|---------|------------------------|---------------------------|--------------|
| SIDC23D120F6 | 1200V   | 25A                    | 3.5 x 6.5 mm <sup>2</sup> | sawn on foil |

### **Mechanical Parameters**

| 3.5 x 6.5<br>22.75<br>2.78 x 5.78<br>120   | mm <sup>2</sup> |  |  |
|--|-----------------|--|--|
| 2.78 x 5.78<br>120   |                 |  |  |
| 120  |                 |  |  |
|  |                 |  |  |
| 450  | μm              |  |  |
| 150  | mm              |  |  |
| 644  |                 |  |  |
| Photoimide   |                 |  |  |
| 3200 nm AlSiCu   |                 |  |  |
| Ni Ag –system  |                 |  |  |
| Electrically conductive epoxy glue and soft solder   |                 |  |  |
| AI, ≤500μm   |                 |  |  |
| Ø 0.65mm; max 1.2mm  |                 |  |  |
| Ambient atmosphere air, Temperature 17°C – 25°0 < 6 month  |                 |  |  |
| Acc. to IEC62258-3: Atmosphere >99% Nitrogen or ine<br>Humidity <25%RH, Temperature 17°C – 25°C, < 6 m   |                 |  |  |
| 3200 nm AlSiCu  Ni Ag –system  Electrically conductive epoxy glue and soft solder  Al, ≤500µm  Ø 0.65mm; max 1.2mm  Ambient atmosphere air, Temperature 17°C – 25°C,  < 6 month  Acc. to IEC62258-3: Atmosphere >99% Nitrogen or inert gas |                 |  |  |



## **Maximum Ratings**

| Parameter  | Symbol                    | Condition                      | Value   | Unit |
|--|---------------------------|--------------------------------|---------|------|
| Repetitive peak reverse voltage                  | $V_{RRM}$                 | <i>T</i> <sub>vj</sub> = 25 °C | 1200    | V    |
| Continuous forward current                       | I <sub>F</sub>            | <i>T</i> <sub>vj</sub> < 150°C | 1)      | _    |
| Maximum repetitive forward current <sup>2)</sup> | I <sub>FRM</sub>          | <i>T</i> <sub>vj</sub> < 150°C | 50      | A    |
| Operating junction and storage temperature       | $T_{\rm vj}, T_{\rm stg}$ |                                | -55+150 | °C   |

<sup>1)</sup> depending on thermal properties of assembly

# **Static Characteristics** (tested on wafer), $T_{vj} = 25$ °C

| Parameter                          | Symbol          | Conditions             | Value |      |      | Unit  |
|------------------------------------|-----------------|------------------------|-------|------|------|-------|
| rarameter                          |                 |                        | min.  | typ. | max. | Ollit |
| Reverse leakage current            | $I_{R}$         | V <sub>R</sub> =1200V  |       |      | 20   | μA    |
| Cathode-Anode breakdown<br>Voltage | V <sub>BR</sub> | I <sub>R</sub> =0.25mA | 1200  |      |      | V     |
| Forward voltage drop               | $V_{F}$         | / <sub>F</sub> =25A    | 1.68  | 2.1  | 2.42 |       |

## Electrical Characteristics (not subject to production test - verified by design/characterization)

| Parameter            |                         | Symbol         | Conditions          | Value |      |      | Unit  |
|----------------------|-------------------------|----------------|---------------------|-------|------|------|-------|
| raiailletei          |                         | Syllibol       | Conditions          | min.  | typ. | max. | Oilit |
| Forward voltage drop | T <sub>vj</sub> = 125°C | V <sub>F</sub> | I <sub>F</sub> =25A |       | 1.8  |      | V     |

# **Further Electrical Characteristics**

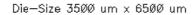
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

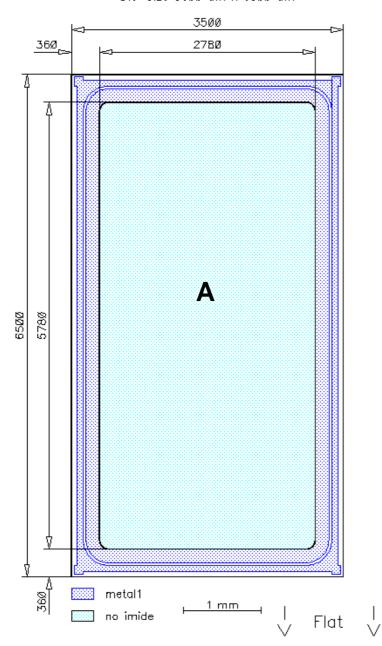
| This chip data sheet refers to the device data sheet |  |
|--|--|
|  |  |

<sup>&</sup>lt;sup>2)</sup> not subject to production test - verified by design/characterisation



# **Chip Drawing**





A: Anode pad



## **Description**

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

### **Revision History**

| Version | Subjects (major changes since last revision) | Date       |  |
|---------|--|------------|--|
| 2.0     | Final data sheet                             | 11.12.2012 |  |
| 2.1     | Operating junction and storage temperature   | 14.05.2013 |  |

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